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(12) **United States Design Patent** (10) **Patent No.:** **US D879,079 S**
Ota (45) **Date of Patent:** **** Mar. 24, 2020**

- (54) **RFID IC TAG INLAY**
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- (51) **LOC (12) Cl.** **14-03**
- (52) **U.S. Cl.**
USPC **D14/230**
- (58) **Field of Classification Search**
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CPC G06K 7/00; G06K 19/00; G06K 19/07749;
G06K 19/07794; H01Q 1/22; H01Q 1/2225; H01Q 1/2283; H01Q 1/243
See application file for complete search history.
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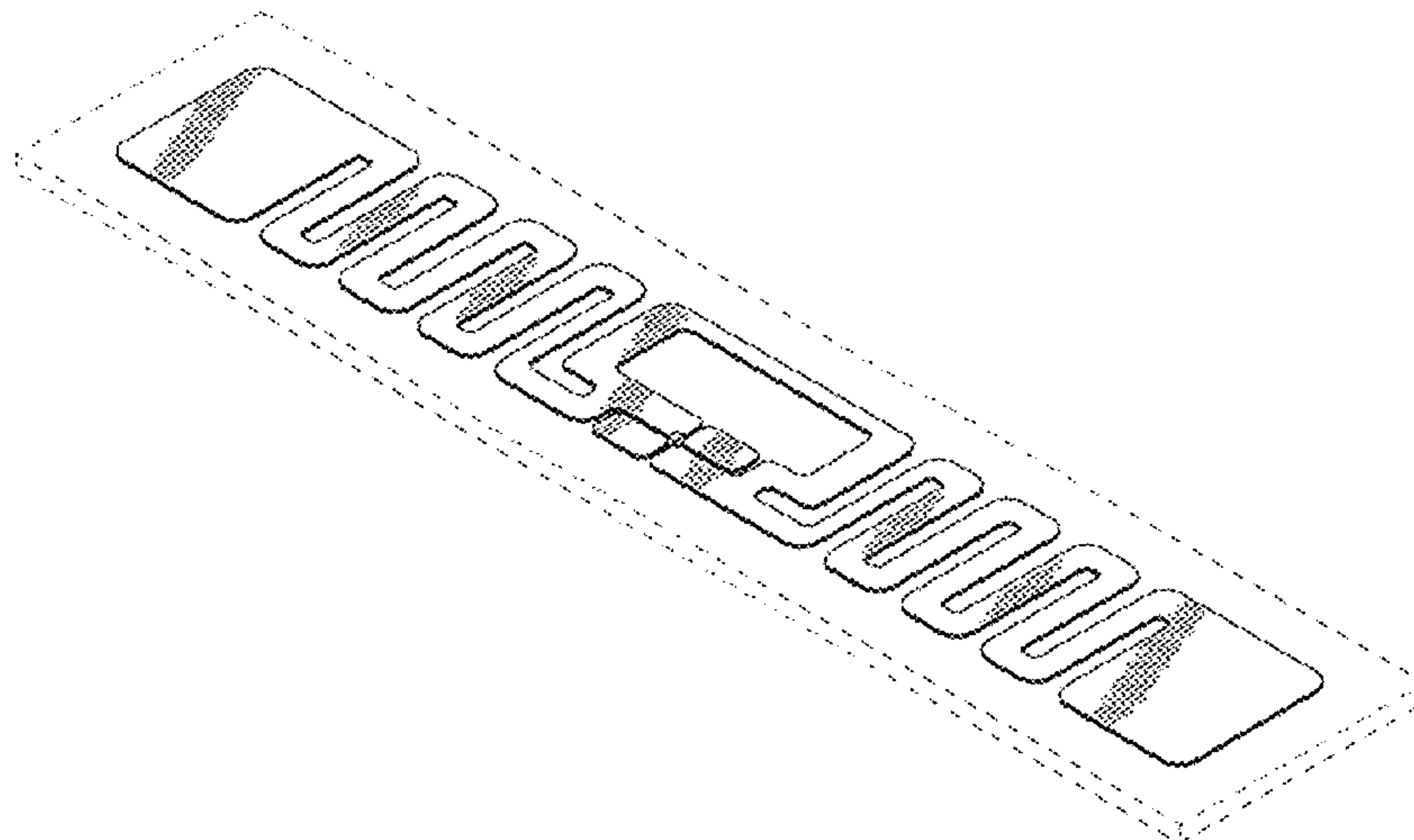
(57) **CLAIM**

The ornamental design for a RFID IC tag inlay, as shown and described.

DESCRIPTION

- 1. RFID IC tag inlay
 - 1.1 : Perspective
 - 1.2 : Front
 - 1.3 : Back
 - 1.4 : Top
 - 1.5 : Bottom
 - 1.6 : Left
 - 1.7 : Right
- The parts shown by means of broken lines in the reproductions are not part of the claimed design.

1 Claim, 7 Drawing Sheets



(56)

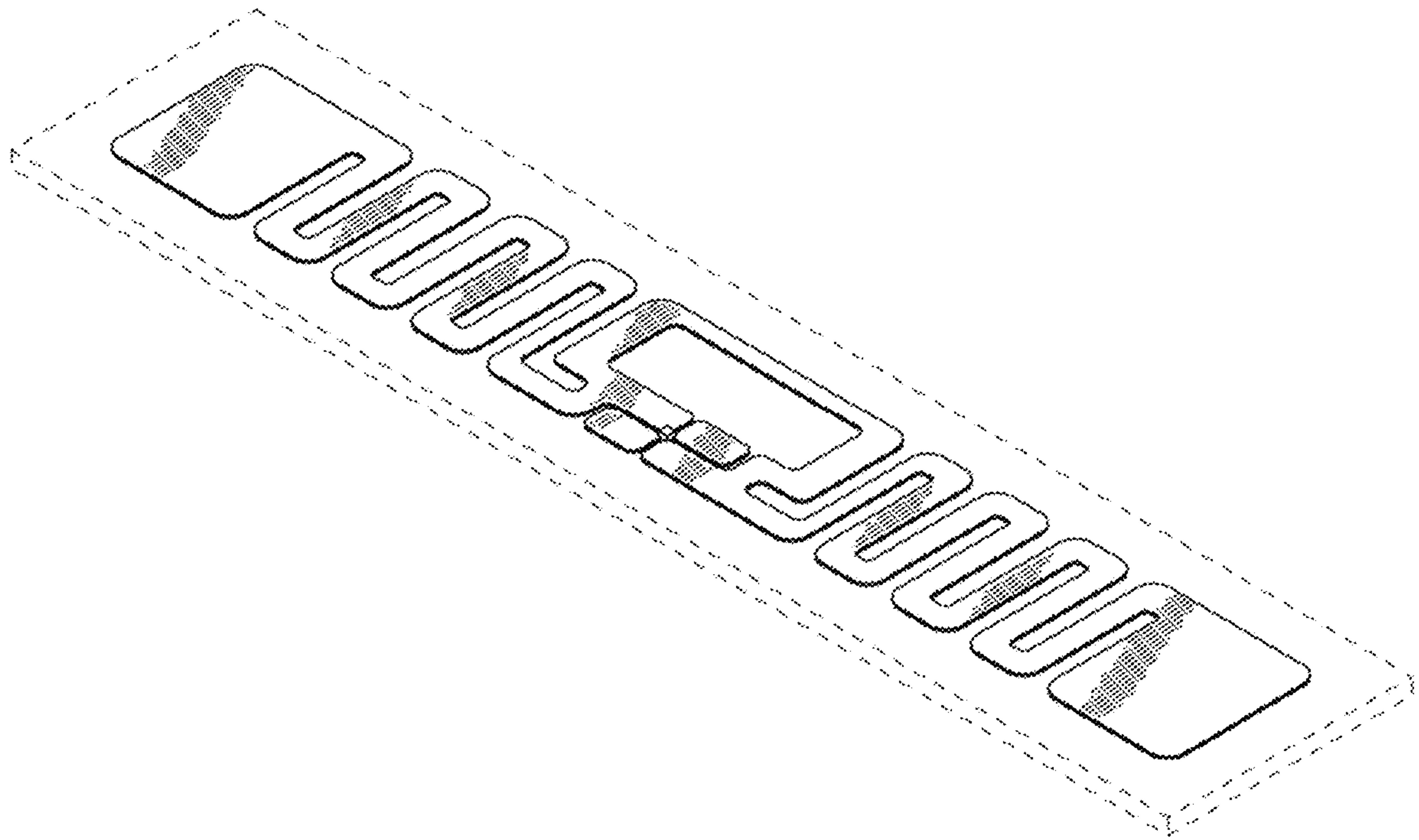
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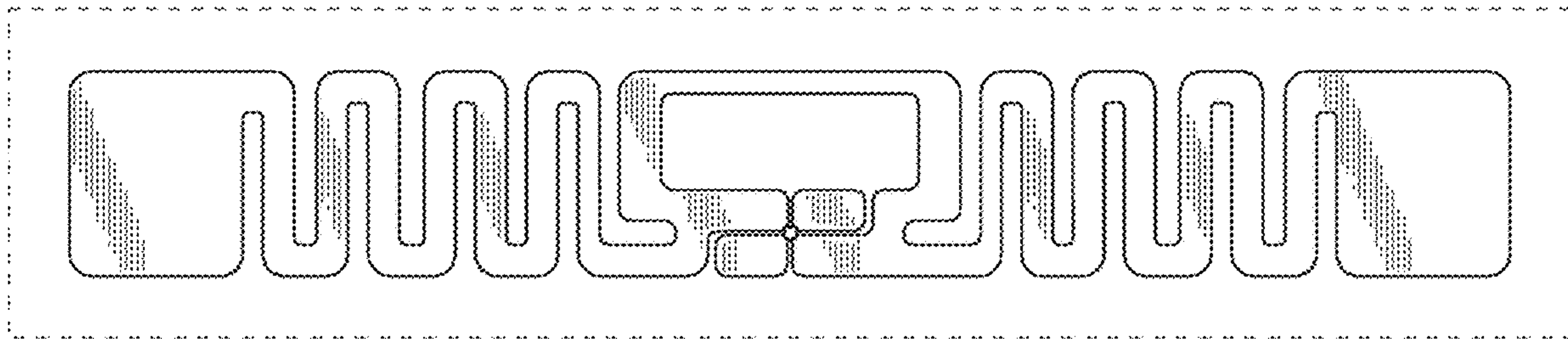
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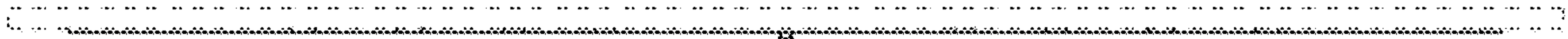
1.2



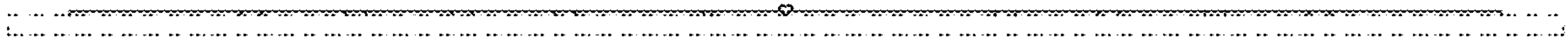
1.3



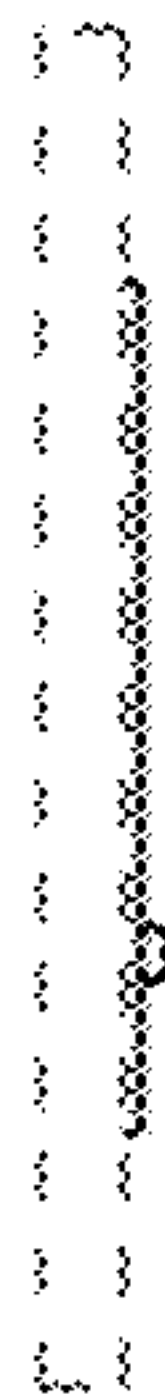
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